P300L 300mm Semiautomatic probing station

The P300L probe station is the most stable, intuitive, space efficient and cost-effective 300mm semiautomatic probe station available today. Designed for low current, sub-micron positioning applications, the P300L comes standard with features such as single-point ground, dry/dark environment, and integrated thermal chuck plumbing. Motorized - programmable controls give a dynamic speed range which supports both precise positioning and long-distance moves. Joystick, script - programmable or netProbe7 control operates the station stage, platen (Z), and theta as well as the microscope X-Y and Z drives.

The P300L's large magnetic stainless steel platen has plenty of room for multiple manipulators and/or a probe card, and features a removable wedge for easy loading and sample accesss.

The system supports a wide choice of options, and is even backward compatible with accessories (manipulators, probe holders, probe card holders) from our industry-standard 8000 series (200mm) stations.

Accurate laser cuts and stable video images are guaranteed by the P300L's massive microscope bridge support structure. The station includes an adjustable microscope lift delay which prevents driving the probes into the microscope objective, a feature that Micromanipulator pioneered, and which is a hallmark of our professional probing systems.

Micromanipulator

1555 Forrest Way Carson City, NV 89706

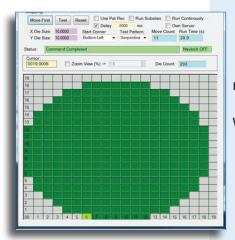
TF : 800.654.5659 PH : 775.882.2400 FX : 775.882.7694



netProbe7 (optional) software



netProbe7 (optional) Navigator



netProbe7 (optional) Wafer Map

netProbe7 (optional) Script Commands



P300L Features and Renefits

- Cast base with vibration isolation interlayer: Provides stability and ruggedness, Stainless steel platen supports both magnetic and vacuum base manipulators
- Station single-point ground: Low current ready
- Motorized stage, platen theta and microscope drives are controllable through joystick, or script-language programmable interface (TCP/IP or RS-232) standard.
- Stage, Platen, Theta (300 x 300 x 50mm x 15 deg) range: Provides full wafer coverage and flexibility of setup
- •. 1.0 micron resolution stage, 2.5 micron resolution platen and microscope drive: Supports probing of the smallest targets
- Stage range 300 x 300 mm (X,Y), accuracy +/- 5 micron, repeatability +/- 5 micron. Platen (Z) range 50 mm, repeatability +/- 2.5 micron. Theta range +/- 7.5 degrees, resolution 0.2 micron.
- Integrated dry/dark enclosure: Provides EMF shield and enclosure for low temperature chuck dryness
- Removable front wedge: Provides easy access to the chuck for loading and unloading wafers when removed, and support for additional manipulators when in place
- Microscope 100 x 100mm (X-Y), x 50mm (Z) drive range: Accuracy
 +/- 5 repeatability +/- 3 microns, planarity +/- 50 microns.
- High force chuck/theta post assembly: Supports high pincount probe card pressures
- Station plumbed and wired to accept -55 to +300 degree C H1000 series thermal chuck: Set up is clean and clear for fixturing and cabling
- Vacuum quick disconnect and Triaxial strain relief brackets: Provide convenient, strain relieved connections.

Programmable axes are also controllable via optional netProbe7 software with its extensive GUI featuring Navigation, Wafer Map, Sub-die and Video applications and Router app for GPIB connectivity (order netProbe7 separately)

Full range of accessories and options available including:

Probe card holders, Light Tight Enclosures, Thermal Chucks, Video accessories, Manual/Motorized manipulators.

Facility Requirements:

- · Test station: Vacuum: 25 in-Hg
- Controller: 85 to 265 VAC, 47-63 Hz, 2.4 Amps, typical

Test Station Dimensions (Width, Depth, Height, Weight):

- Station: 33" x 40" x 33" (84 x 102 x 84 cm), 480 lbs (218-Kg)
- Controller separate dimensions depend on configuration.